**3GPP TSG- Meeting # *7491***

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| *CR-Form-v12.2* |
| **CHANGE REQUEST** |
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|  | **1-1** | **CR** |  | **rev** |  | **Current version:** |  |  |
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| *For* [***HE******LP***](http://www.3gpp.org/3G_Specs/CRs.htm#_blank)*on using this form: comprehensive instructions can be found at* [*http://www.3gpp.org/Change-Requests*](http://www.3gpp.org/Change-Requests)*.* |
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| ***Proposed change affects:*** | UICC apps |  | ME |  | Radio Access Network | **X** | Core Network |  |

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| ***Title:***  | Big CR for TS 38.141-1 Maintenance RF part (Rel-15, CAT F) |
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| ***Source to WG:*** | MCC,  |
| ***Source to TSG:*** |  |
|  |  |
| ***Work item code:*** | NR\_newRAT-Perf |  | ***Date:*** | 2022-3-6 |
|  |  |  |  |  |
| ***Category:*** | F |  | ***Release:*** |  |
|  | *Use one of the following categories:****F*** *(correction)****A*** *(mirror corresponding to a change in an earlier release)****B*** *(addition of feature),* ***C*** *(functional modification of feature)****D*** *(editorial modification)*Detailed explanations of the above categories canbe found in 3GPP [TR 21.900](http://www.3gpp.org/ftp/Specs/html-info/21900.htm). | *Use one of the following releases:Rel-8 (Release 8)Rel-9 (Release 9)Rel-10 (Release 10)Rel-11 (Release 11)…Rel-16 (Release 16)Rel-17 (Release 17)Rel-18 (Release 18)Rel-19 (Release 19)* |
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| ***Reason for change:*** | This big CR merges the multiple endorsed draft CRs. The reason for change in each endorsed draft CR is copied below.**R4-2207295, Draft CR to 38.141-1: Clarification on unwanted emission testing**RMS detection mode is defined while the required measurement duration is not clarified in current specifications. |
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| ***Summary of change:*** |  The summary of change in each each endorsed draft CR is copied below.**R4-2207295, Draft CR to 38.141-1: Clarification on unwanted emission testing**Clarification on required average time for emission test is added in clause 6.6 and 6.7. |
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| ***Consequences if not approved:*** | The consequences if not approved for each endorsed draft CR are copied below.**R4-2207295, Draft CR to 38.141-1: Clarification on unwanted emission testing**The general rule for required average time for emission test is missing. |
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| ***Clauses affected:*** | The clauses affected in each endorsed draft CR are copied below.**R4-2207295, Draft CR to 38.141-1: Clarification on unwanted emission testing**6.6.4.4.2, 6.6.5.4.2, 6.7.4.2 |
|  |  |
|  | **Y** | **N** |  |  |
| ***Other specs*** |  | **x** |  Other core specifications  | TS/TR ... CR ...  |
| ***affected:*** |  | **x** |  Test specifications | TS/TR ... CR ...  |
| ***(show related CRs)*** |  | **x** |  O&M Specifications | TS/TR ... CR ...  |
|  |  |
| ***Other comments:*** |  |
|  |  |
| ***This CR's revision history:*** |  |

## **<Start of Change 1>**

##### 6.6.4.4.2 Procedure

For *BS type 1-H* where there may be multiple *TAB connectors*, they may be tested one at a time or multiple *TAB connectors* may be tested in parallel as shown in annex D.3.1. Whichever method is used the procedure is repeated until all *TAB connectors* necessary to demonstrate conformance have been tested.

1) Connect the *single-band connector* or *multi-band connector* under test to measurement equipment as shown in annex D.1.1 for *BS type 1-C* or in annex D.3.1 for *BS type 1-H*. All connectors not under test shall be terminated.

 As a general rule, the resolution bandwidth of the measuring equipment should be equal to the measurement bandwidth. However, to improve measurement accuracy, sensitivity, efficiency and avoiding e.g. carrier leakage, the resolution bandwidth may be smaller than the measurement bandwidth. When the resolution bandwidth is smaller than the measurement bandwidth, the result should be integrated over the measurement bandwidth in order to obtain the equivalent noise bandwidth of the measurement bandwidth.

 The measurement device characteristics shall be:

- Detection mode: True RMS.

 The emission power should be averaged over an appropriate time duration to ensure the measurement is within the measurement uncertainty in Table 4.1.2.2-1.

2) For a connectors declared to be capable of single carrier operation only, set the representative connectors under test to transmit according to the applicable test configuration in clause 4.8 at *rated carrier output power* Prated,c,AC for *BS type 1-C* and Prated,c,TABC for *BS type 1-H* (D.21). Channel set-up shall be according to NR-FR1-TM 1.1.

 For a connector under test declared to be capable of multi-carrier and/or CA operation set the connector under test to transmit on all carriers configured using the applicable test configuration and corresponding power setting specified in clauses 4.7 and 4.8 using the corresponding test models or set of physical channels in clause 4.9.2.

3) Step the centre frequency of the measurement filter in contiguous steps and measure the emission within the specified frequency ranges with the specified measurement bandwidth. For connector under test declared to operate in multiple bands or non-contiguous spectrum, the emission within the *Inter RF Bandwidth* or *sub-block gap* shall be measured using the specified measurement bandwidth from the closest RF Bandwidth or sub block edge.

4) Repeat the test for the remaining test cases, with the channel set-up according to NR-FR1-TM 1.2.

In addition, for *multi-band connectors*, the following steps shall apply:

5) For a *multi-band connectors* and single band tests, repeat the steps above per involved *operating band* where single band test configurations and test models shall apply with no carrier activated in the other *operating band*.

## **<End of Change 1>**

## **<Start of Change 2>**

##### 6.6.5.4.2 Procedure

For *BS type 1-H* where there may be multiple *TAB connectors*, they may be tested one at a time or multiple *TAB connectors* may be tested in parallel as shown in annex D.3.1. Whichever method is used the procedure is repeated until all *TAB connectors* necessary to demonstrate conformance have been tested.

1) Connect the *single-band connector* or *multi-band connector* under test to measurement equipment as shown in annex D.1.1 for *BS type 1-C* and in annex D.3.1 for *BS type 1-H*. All connectors not under test shall be terminated.

2) Measurements shall use a measurement bandwidth in accordance to the conditions in clause 6.6.5.5.

 The measurement device characteristics shall be:

- Detection mode: True RMS.

 The emission power should be averaged over an appropriate time duration to ensure the measurement is within the measurement uncertainty in Table 4.1.2.2-1.

3) For a connectors declared to be capable of single carrier operation only (D.16), set the representative connectors under test to transmit according to the applicable test configuration in clause 4.8 at *rated carrier output power* (Prated,c,AC, or Prated,c,TABC, D.21). Channel set-up shall be according to NR-FR1-TM 1.1.

 For a connector under test declared to be capable of multi-carrier and/or CA operation (D.15-D.16) set the connector under test to transmit on all carriers configured using the applicable test configuration and corresponding power setting specified in clauses 4.7 and 4.8 using the corresponding test models or set of physical channels in clause 4.9.2.

4) Measure the emission at the specified frequencies with specified measurement bandwidth.

In addition, for *multi-band connectors*, the following steps shall apply:

5) For a *multi-band connectors* and single band tests, repeat the steps above per involved *operating band* where single band test configurations and test models shall apply with no carrier activated in the other *operating band*.

## **<End of Change 2>**

## **<Start of Change 3>**

#### 6.7.4.2 Procedure

For *BS type 1-H* where there may be multiple *TAB connectors*, they may be tested one at a time or multiple *TAB connectors* may be tested in parallel as shown in annex D.3.1. Whichever method is used the procedure is repeated until all *TAB connectors* necessary to demonstrate conformance have been tested.

1) Connect the *single-band connector* or *multi-band connector* under test to measurement equipment as shown in annex D.1.2 for *BS type 1-C* and in annex D.3.2 for *BS type 1-H*. All connectors not under test shall be terminated.

2) The measurement device characteristics shall be:

- Detection mode: True RMS.

 The emission power should be averaged over an appropriate time duration to ensure the measurement is within the measurement uncertainty in Table 4.1.2.2-1.

3) For a connectors declared to be capable of single carrier operation only (D.16), set the representative connectors under test to transmit according to the applicable test configuration in clause 4.8 at *rated carrier output power* Prated,c,AC for *BS type 1-C* and Prated,c,TABC for *BS type 1-H* (D.21). Channel set-up shall be according to NR-FR1-TM 1.1.

 For a connector under test declared to be capable of multi-carrier and/or CA operation (D.15-D.16) set the connector under test to transmit on all carriers configured using the applicable test configuration and corresponding power setting specified in clauses 4.7 and 4.8 using the corresponding test models or set of physical channels in clause 4.9.2.

4) Generate the interfering signal according to NR-FR1-TM-1.1, as defined in clause 4.9.2, with the minimum channel bandwidth (BWChannel) with 15 kHz SCS of the band defined in clause 5.3.5 of TS 38.104 [2] and a centre frequency offset from the lower/upper edge of the wanted signal or edge of sub-block inside a sub-block gap , for n = 1, 2 and 3, but exclude interfering frequencies that are outside of the allocated downlink operating band or interfering frequencies that are not completely within the sub-block gap or within the *Inter RF Bandwidth gap*.

5) Adjust ATT attenuator (as in the test setup in annex D.1.2 for *BS type 1-C* and in annex D.3.2 for *BS type 1-H*) so that level of the interfering signal is as defined in clause 6.7.5.

6) Perform the unwanted emission tests specified in clauses 6.6.3 and 6.6.4 for all third and fifth order intermodulation products which appear in the frequency ranges defined in clauses 6.6.3 and 6.6.4. The width of the intermodulation products shall be taken into account.

7) Perform the transmitter spurious emissions test as specified in clause 6.6.5, for all third and fifth order intermodulation products which appear in the frequency ranges defined in clause 6.6.5. The width of the intermodulation products shall be taken into account.

8) Verify that the emission level does not exceed the required level in clause 6.7.5 with the exception of interfering signal frequencies.

9) Repeat the test for the remaining interfering signal centre frequency offsets according to step 4.

10) Repeat the test for the remaining test signals defined in clause 6.7.5 for additional requirements and for *BS type 1-H* intra-system requirements.

In addition, for *multi-band connectors*, the following steps shall apply:

11) For a *multi-band connectors* and single band tests, repeat the steps above per involved *operating band* where single band test configurations and test models shall apply with no carrier activated in the other *operating band*.

NOTE: The third order intermodulation products are centred at 2F1±F2 and 2F2±F1. The fifth order intermodulation products are centred at 3F1±2F2, 3F2±2F1, 4F1±F2, and 4F2±F1 where F1 represents the test signal centre frequency or centre frequency of each sub-block and F2 represents the interfering signal centre frequency. The widths of intermodulation products are:

- (n\*BWF1 + m\* BWF2) for the nF1±mF2 products;

- (n\* BWF2 + m\* BWF1) for the nF2±mF1 products;

 where BWF1 represents the test wanted signal RF bandwidth or channel bandwidth in case of single carrier, or sub-block bandwidth and BWF2 represents the interfering signal channel bandwidth.

## **<End of Change 3>**